

<b>Notice of References Cited</b>		Application/Control No. 09/709,993	Applicant(s)/Patent Under Reexamination BROWN ET AL.	
		Examiner Clement B Graham	Art Unit 3628	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-		Blank	
	B	US-3,842,248	10-1974	Yarnell et al.	705/34
	C	US-3,852,571	12-1974	Hall et al.	235/379
	D	US-4,485,300	11-1984	Peirce, Roger	235/380
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	K	US-			
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